

Search Notes

Application/Control No.

10/784,176

Examiner

Tim Heitbrink

Applicant(s)/Patent under
Reexamination

UCHIYAMA ET AL.

Art Unit

1722

SEARCHED

Class	Subclass	Date	Examiner
425	143	5/22/2006	TWH
425	144	5/22/2006	TWH
264	40.6	5/22/2006	TWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR